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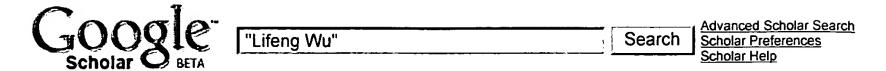Technical Report: CU-CS-930-02 ☐ Amer Diwan, Han Lee ...
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